

ABSTRACT OF THE DISCLOSURE

The present invention discloses a method for testing a non-volatile memory, characterized in that the code assigned by the client is written in at least one non-volatile memory in advance, and then a particular pin of the non-volatile memory is cut, such as a write enabling pin for avoiding the mistake of rewriting. After restarting a testing machine, the code written in the non-volatile memory is read out to compare it with the code retrieved from a controlling program of the testing machine. If the comparing result is identical, it means that the code retrieved by the controlling program of the testing machine is correct; otherwise, the code retrieved by the controlling program is incorrect.

11 12 13 14 15 16 17 18 19 20 21 22 23 24 25 26 27 28 29 30 31 32 33 34 35 36 37 38 39 40 41 42 43 44 45 46 47 48 49 50 51 52 53 54 55 56 57 58 59 60 61 62 63 64 65 66 67 68 69 70 71 72 73 74 75 76 77 78 79 80 81 82 83 84 85 86 87 88 89 90 91 92 93 94 95 96 97 98 99 100